



YEA SHIN TECHNOLOGY CO., LTD

YS30N06BA

## N-Channel Enhancement MOSFET

**V<sub>DS</sub>= 30V, I<sub>D</sub>= 40A**



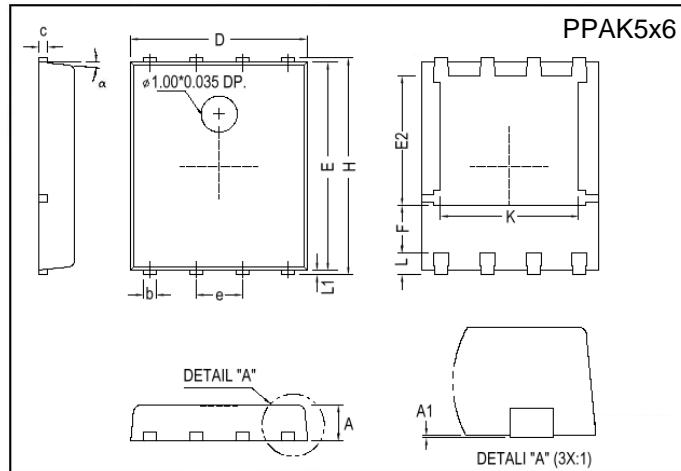
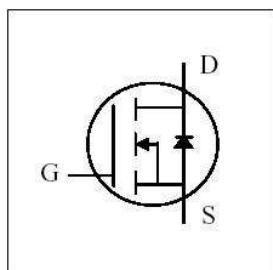
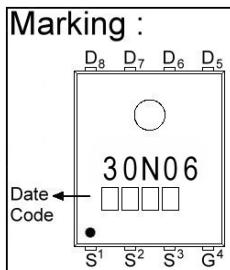
### DESCRIPTION

The YS30N06BA uses advanced Trench technology and designs to provide excellent  $R_{DS(ON)}$  with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications.

The YS30N06BA meet the RoHS and Green Product requirement, 100% EAS and Rg guaranteed with full function reliability approved.

### FEATURES

- Low On-Resistance
- Low Input Capacitance
- Green Device Available
- Low Miller Charge
- 100% EAS and Rg Guaranteed



REF.	Millimeter			REF.	Millimeter		
	Min.	Nom.	Max.		Min.	Nom.	Max.
A	0.85	1.00	1.15	E	5.70	-	5.90
A1	0.00	-	0.10	e	-	1.27	-
b	0.30	-	0.51	H	5.90	-	6.20
c	0.20	-	0.30	L	-	0.60	-
D	4.80	-	5.00	L1	0.06	-	0.20
F	1.10REF.			$\alpha$	0°	-	12°
E2	3.50REF.			K	3.70	3.90	4.10

### Absolute Maximum Ratings

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D @ T_C=25^\circ C$	40	A
	$I_D @ T_C=70^\circ C$	40	A
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	100	A
Continuous Drain Current	$I_D @ T_A=25^\circ C$	31	A
	$I_D @ T_A=70^\circ C$	25	A
Total Power Dissipation	$P_D @ T_C=25^\circ C$	36	W
	$P_D @ T_A=25^\circ C$	4.2	W
Single Pulse Avalanche Energy, L=0.1mH	$E_{AS}$	72	mJ
Single Pulse Avalanche Current, L=0.1mH	$I_{AS}$	38	A
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 ~ +150	°C

### Thermal Data

Parameter	Symbol	Conditions	Max. Value	Unit
Thermal Resistance Junction-ambient <sup>2</sup>	$R_{\theta JA}$	Steady State	30	°C/W
Thermal Resistance Junction-case <sup>2</sup>	$R_{\theta JC}$	Steady State	3.5	°C/W

# DEVICE CHARACTERISTICS

## YS30N06BA

### Electrical Characteristics ( $T_J = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	30	-	-	V	$\text{V}_{\text{GS}}=0, \text{I}_D=250\mu\text{A}$
Gate Threshold Voltage	$\text{V}_{\text{GS}(\text{th})}$	1.15	-	2.2	V	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$
Forward Transconductance <sup>1</sup>	$\text{g}_{\text{fs}}$	-	82	-	S	$\text{V}_{\text{DS}}=15\text{V}, \text{I}_D=19\text{A}$
Gate-Source Leakage Current	$\text{I}_{\text{GSS}}$	-	-	$\pm 100$	nA	$\text{V}_{\text{GS}}= \pm 20\text{V}$
Drain-Source Leakage Current	$\text{I}_{\text{DSS}}$	-	-	1	$\mu\text{A}$	$\text{V}_{\text{DS}}=30\text{V}, \text{V}_{\text{GS}}=0$
Static Drain-Source On-Resistance <sup>1</sup>	$\text{R}_{\text{DS}(\text{ON})}$	-	3.3	4.5	$\text{m}\Omega$	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=19\text{A}$
		-	4.6	5.6		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_D=16\text{A}$
Total Gate Charge <sup>1</sup>	$\text{Q}_{\text{g}}$	-	12	-	nC	$\text{I}_D=19\text{A}$ $\text{V}_{\text{DS}}=15\text{V}$ $\text{V}_{\text{GS}}=4.5\text{V}$
Gate-Source Charge	$\text{Q}_{\text{gs}}$	-	6	-		
Gate-Drain ("Miller") Change	$\text{Q}_{\text{gd}}$	-	5	-		
Turn-on Delay Time <sup>1</sup>	$\text{T}_{\text{d}(\text{on})}$	-	24	-	ns	$\text{V}_{\text{DS}}=15\text{V}$ $\text{I}_D=10\text{A}$ $\text{V}_{\text{GS}}=4.5\text{V}$ $\text{R}_G=1.0\Omega$ $\text{R}_L=1.5\Omega$
Rise Time	$\text{T}_{\text{r}}$	-	21	-		
Turn-off Delay Time	$\text{T}_{\text{d}(\text{off})}$	-	25	-		
Fall Time	$\text{T}_{\text{f}}$	-	17	-		
Input Capacitance	$\text{C}_{\text{iss}}$	-	1750	-	pF	$\text{V}_{\text{GS}}=0\text{V}$ $\text{V}_{\text{DS}}=15\text{V}$ $f=1.0\text{MHz}$
Output Capacitance	$\text{C}_{\text{oss}}$	-	360	-		
Reverse Transfer Capacitance	$\text{C}_{\text{rss}}$	-	150	-		
Gate Resistance	$\text{R}_{\text{g}}$	-	3.2	5.0	$\Omega$	$f=1.0\text{MHz}$

### Guaranteed Avalanche Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Single Pulse Avalanche Energy <sup>3</sup>	EAS	48	-	-	mJ	$\text{V}_{\text{DD}}=20\text{V}, \text{L}=0.1\text{mH}, \text{I}_{\text{AS}}=31\text{A}$

### Source-Drain Diode

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Diode Forward Voltage <sup>1</sup>	$\text{V}_{\text{SD}}$	-	0.8	1.2	V	$\text{I}_{\text{S}}=10\text{A}, \text{V}_{\text{GS}}=0\text{V}$
Continuous Source Current <sup>1</sup>	$\text{I}_{\text{S}}$	-	-	40	A	---
Reverse Recovery Time	$\text{t}_{\text{rr}}$	-	25	-	ns	$\text{I}_{\text{F}}=10\text{A}, \text{dI}/\text{dt}=100\text{A}/\mu\text{s},$
Reverse Recovery Charge	$\text{Q}_{\text{rr}}$	-	17	-	nC	$\text{T}_J=25^\circ\text{C}$

Notes: 1. The data tested by pulsed, pulse width  $\leq 300\text{us}$ , duty cycle  $\leq 2\%$ .

2.  $\text{R}_{\theta\text{JA}}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $\text{R}_{\theta\text{JC}}$  is guaranteed by design while  $\text{R}_{\theta\text{CA}}$  is determined by the user's board design.  $\text{R}_{\theta\text{JA}}$  shown below for single device operation on FR-4 in still air.

3. The Min. value is 100% EAS tested guarantee.

# DEVICE CHARACTERISTICS

YS30N06BA

## Typical Characteristics

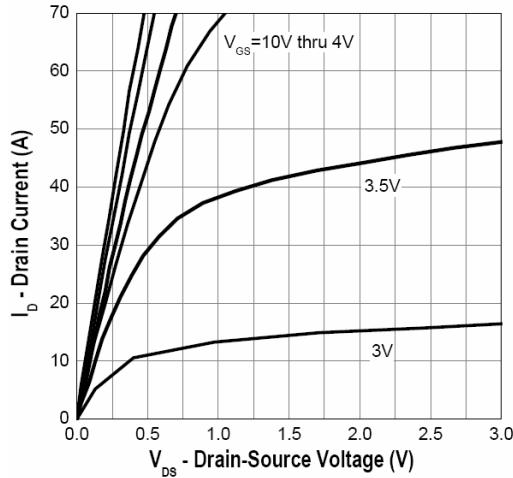


Fig.1 Typical Output Characteristics

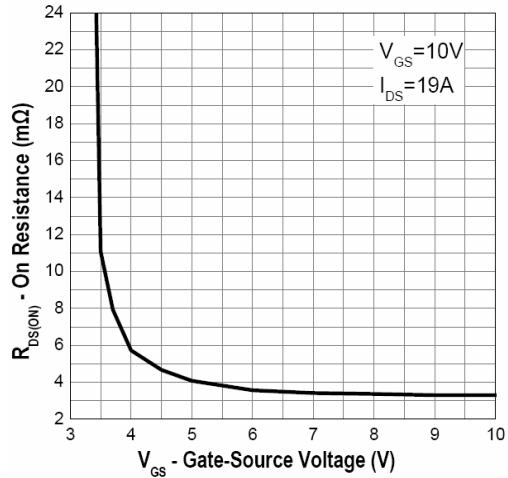


Fig.2 On-Resistance vs. G-S Voltage

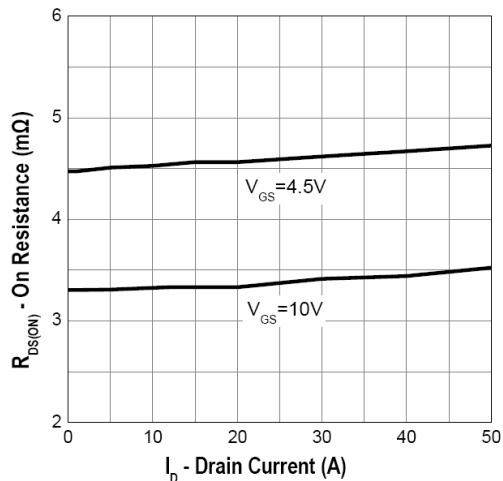


Fig.3 On-Resistance vs. Drain Current

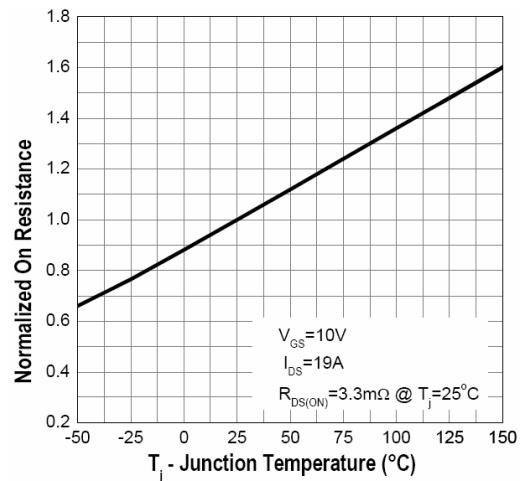


Fig.4 Normalized  $R_{DS(ON)}$  vs.  $T_j$

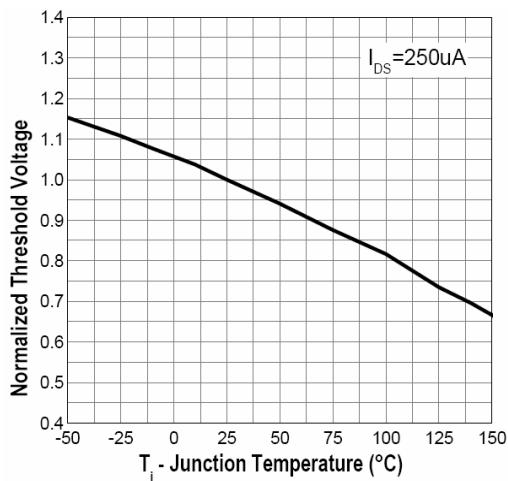


Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_j$

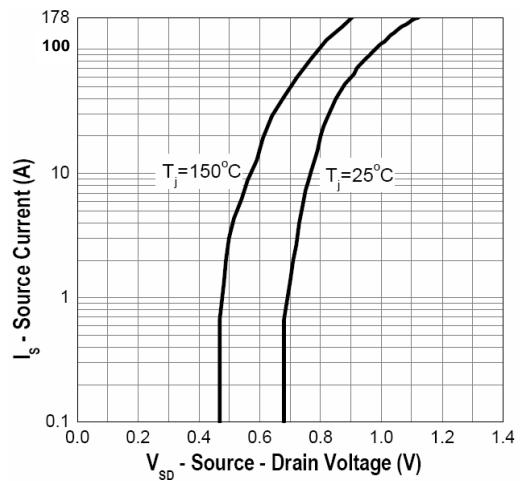


Fig.6 Forward Characteristics of Reverse

# DEVICE CHARACTERISTICS

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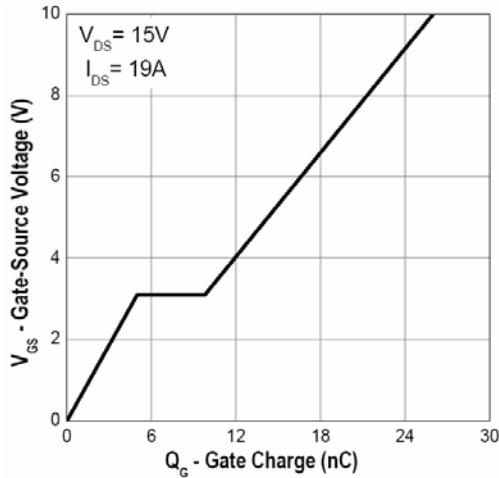


Fig.7 Gate Charge Characteristics

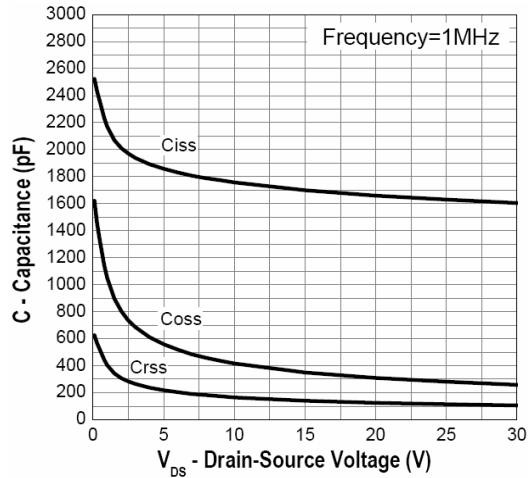


Fig.8 Capacitance Characteristics

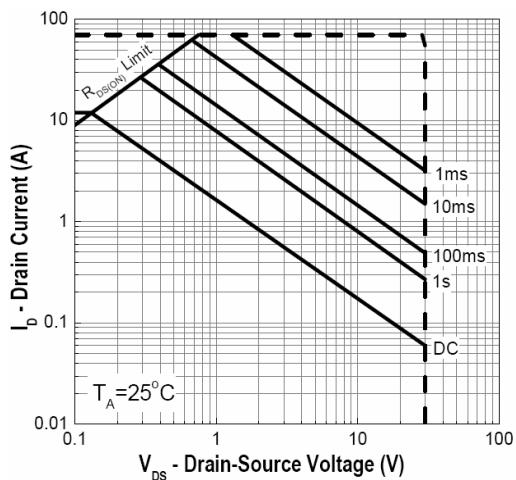


Fig.9 Safe Operating Area

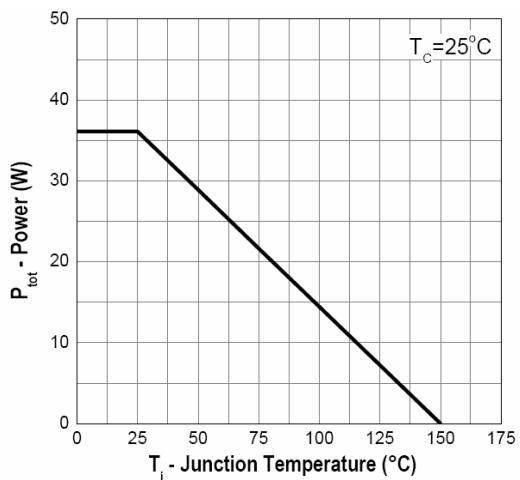


Fig.10 Power Dissipation

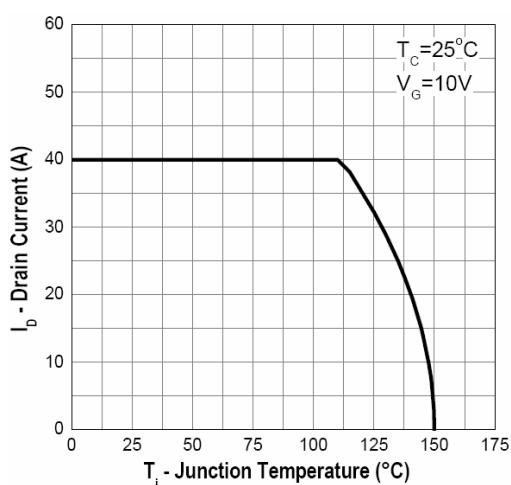


Fig.11 Drain Current vs.  $T_j$

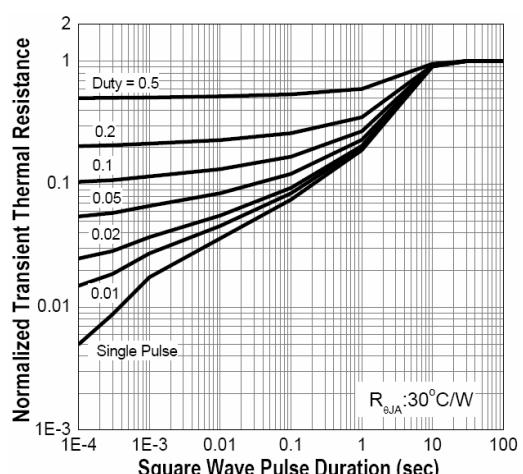


Fig.12 Transient Thermal Impedance